# 74AVCH16T245

16-bit dual supply translating transceiver with configurable voltage translation; 3-state

Rev. 02 — 29 March 2010

Product data sheet

### 1. General description

The 74AVCH16T245 is a 16-bit transceiver with bidirectional level voltage translation and 3-state outputs. The device can be used as two 8-bit transceivers or as a 16-bit transceiver. It has dual supplies ( $V_{CC(A)}$  and  $V_{CC(B)}$ ) for voltage translation and two 8-bit input-output ports (nAn, nBn) each with its own output enable ( $n\overline{OE}$ ) and send/receive (nDIR) input for direction control.  $V_{CC(A)}$  and  $V_{CC(B)}$  can be independently supplied at any voltage between 0.8 V and 3.6 V making the device suitable for low voltage translation between any of the following voltages: 0.8 V, 1.2 V, 1.5 V, 1.8 V, 2.5 V and 3.3 V. A HIGH on nDIR selects transmission from nAn to nBn while a LOW on nDIR selects transmission from nBn to nAn. A HIGH on  $n\overline{OE}$  causes the outputs to assume a high-impedance OFF-state

The device is fully specified for partial power-down applications using  $I_{OFF}$ . The  $I_{OFF}$  circuitry disables the output, preventing any damaging backflow current through the device when it is powered down. In suspend mode when either  $V_{CC(A)}$  or  $V_{CC(B)}$  are at GND level, both A and B outputs are in the high-impedance OFF-state. The bus-hold circuitry on the powered-up side always stays active.

The 74AVCH16T245 has active bus hold circuitry which is provided to hold unused or floating data inputs at a valid logic level. This feature eliminates the need for external pull-up or pull-down resistors.

#### 2. Features and benefits

- Wide supply voltage range:
  - ◆ V<sub>CC(A)</sub>: 0.8 V to 3.6 V
  - ◆ V<sub>CC(B)</sub>: 0.8 V to 3.6 V
- Complies with JEDEC standards:
  - ◆ JESD8-12 (0.8 V to 1.3 V)
  - ◆ JESD8-11 (0.9 V to 1.65 V)
  - ◆ JESD8-7 (1.2 V to 1.95 V)
  - ◆ JESD8-5 (1.8 V to 2.7 V)
  - ◆ JESD8-B (2.7 V to 3.6 V)
- ESD protection:
  - HBM JESD22-A114F Class 3B exceeds 8000 V
  - MM JESD22-A115-A exceeds 200 V
  - CDM JESD22-C101D exceeds 1000 V
- Maximum data rates:
  - ◆ 380 Mbit/s (≥ 1.8 V to 3.3 V translation)



- ◆ 200 Mbit/s (≥ 1.1 V to 3.3 V translation)
- ◆ 200 Mbit/s (≥ 1.1 V to 2.5 V translation)
- ◆ 200 Mbit/s (≥ 1.1 V to 1.8 V translation)
- ◆ 150 Mbit/s (≥ 1.1 V to 1.5 V translation)
- ◆ 100 Mbit/s (≥ 1.1 V to 1.2 V translation)
- Suspend mode
- Bus hold on data inputs
- Latch-up performance exceeds 100 mA per JESD 78 Class II
- Inputs accept voltages up to 3.6 V
- I<sub>OFF</sub> circuitry provides partial Power-down mode operation
- Multiple package options
- Specified from -40 °C to +85 °C and -40 °C to +125 °C

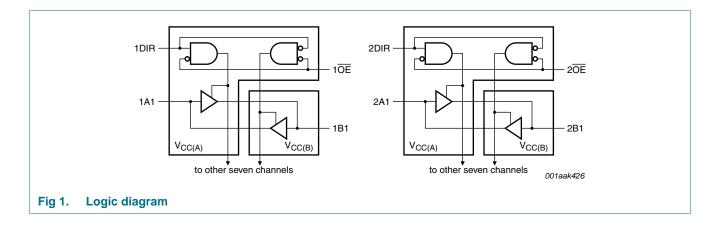
# 3. Ordering information

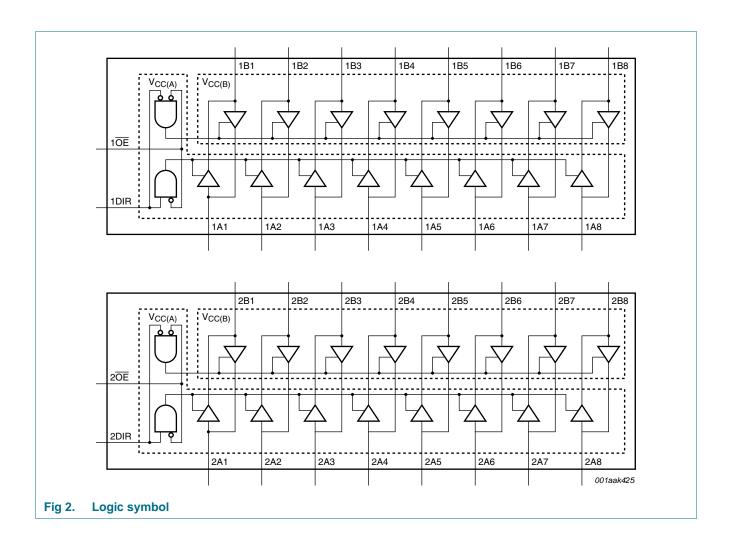
Table 1. Ordering information

Type number	Package							
	Temperature range	Name	Description	Version				
74AVCH16T245DGG	−40 °C to +125 °C	TSSOP48	plastic thin shrink small outline package; 48 leads; body width 6.1 mm	SOT362-1				
74AVCH16T245DGV	–40 °C to +125 °C	TSSOP48[1]	plastic thin shrink small outline package; 48 leads; body width 4.4 mm; lead pitch 0.4 mm	SOT480-1				
74AVCH16T245EV	–40 °C to +125 °C	VFBGA56	plastic very thin fine-pitch ball grid array package; 56 balls; body 4.5 $\times$ 7 $\times$ 0.65 mm	SOT702-1				
74AVCH16T245BQ	–40 °C to +125 °C	HXQFN60U	plastic thermal enhanced extremely thin quad flat package; no leads; 60 terminals; UTLP based; body $4\times6\times0.5$ mm	SOT1134-1				

<sup>[1]</sup> Also known as TVSOP48.

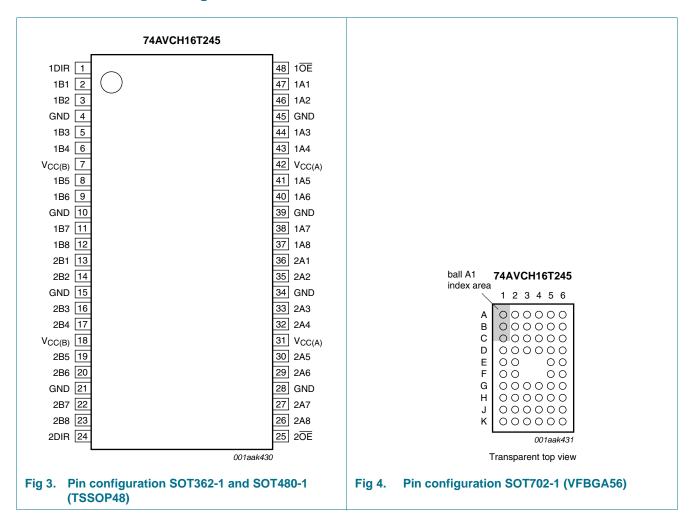
### 4. Functional diagram





# 5. Pinning information

### 5.1 Pinning



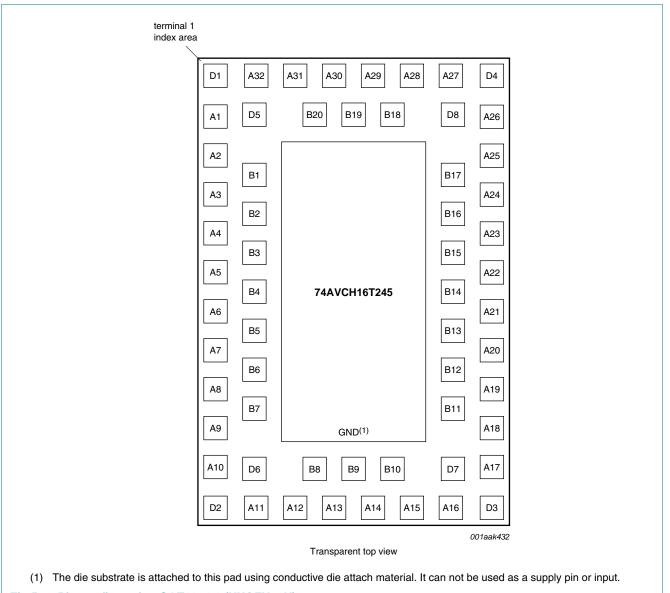


Fig 5. Pin configuration SOT1134-1 (HXQFN60U)

### 5.2 Pin description

Table 2. Pin description

Symbol	Pin			Description
	SOT362-1 and SOT480-1	SOT702-1	SOT1134-1	
1DIR, 2DIR	1, 24	A1, K1	A30, A13	direction control
1B1 to 1B8	2, 3, 5, 6, 8, 9, 11, 12	B2, B1, C2, C1, D2, D1, E2, E1	B20, A31, D5, D1, A2, B2, B3, A5	data input or output
2B1 to 2B8	13, 14, 16, 17, 19, 20, 22, 23	F1, F2, G1, G2, H1, H2, J1, J2	A6, B5, B6, A9, D2, D6, A12, B8	data input or output
GND <mark><sup>11</sup></mark>	4, 10, 15, 21, 28, 34, 39, 45	B3, D3, G3, J3, J4, G4, D4, B4	A32, A3, A8, A11, A16, A19, A24, A27	ground (0 V)
$V_{CC(B)}$	7, 18	C3, H3	A1, A10	supply voltage B (nBn inputs are referenced to $V_{\text{CC(B)}}$ )
10E, 20E	48, 25	A6, K6	A29, A14	output enable input (active LOW)
1A1 to 1A8	47, 46, 44, 43, 41, 40, 38, 37	B5, B6, C5, C6, D5, D6, E5, E6	B18, A28, D8, D4, A25, B16, B15, A22	data input or output
2A1 to 2A8	36, 35, 33, 32, 30, 29, 27, 26	F6, F5, G6, G5, H6, H5, J6, J5	A21, B13, B12, A18, D3, D7, A15, B10	data input or output
V <sub>CC(A)</sub>	31, 42	C4, H4	A17, A26	supply voltage A (nAn, n $\overline{\text{OE}}$ and nDIR inputs are referenced to $V_{\text{CC(A)}}$ )
n.c.	-	A2, A3, A4, A5, K2, K3, K4, K5	A4, A7, A20, A23, B1, B4, B7, B9, B11, B14, B17, B19	not connected

<sup>[1]</sup> All GND pins must be connected to ground (0 V).

# 6. Functional description

Table 3. Function table[1]

Supply voltage	Input	Input I		Input/output[3]		
V <sub>CC(A)</sub> , V <sub>CC(B)</sub>	nOE[2]	nDIR[2]	nAn[2]	nBn[2]		
0.8 V to 3.6 V	L	L	nAn = nBn	input		
0.8 V to 3.6 V	L	Н	input	nBn = nAn		
0.8 V to 3.6 V	Н	Χ	Z	Z		
GND[3]	Χ	Χ	Z	Z		

<sup>[1]</sup> H = HIGH voltage level; L = LOW voltage level; X = don't care; Z = high-impedance OFF-state.

<sup>[2]</sup> The nAn, nDIR and n $\overline{\text{OE}}$  input circuit is referenced to  $V_{\text{CC(A)}}$ ; The nBn input circuit is referenced to  $V_{\text{CC(B)}}$ .

<sup>[3]</sup> If at least one of  $V_{CC(A)}$  or  $V_{CC(B)}$  is at GND level, the device goes into suspend mode.

# 7. Limiting values

Table 4. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134). Voltages are referenced to GND (ground = 0 V).

Symbol	Parameter	Conditions	Min	Max	Unit
$V_{CC(A)}$	supply voltage A		-0.5	+4.6	V
V <sub>CC(B)</sub>	supply voltage B		-0.5	+4.6	V
I <sub>IK</sub>	input clamping current	V <sub>I</sub> < 0 V	<b>–50</b>	-	mA
VI	input voltage		<u>[1]</u> –0.5	+4.6	V
I <sub>OK</sub>	output clamping current	V <sub>O</sub> < 0 V	-50	-	mA
Vo	output voltage	Active mode	[1][2][3] -0.5	$V_{CCO} + 0.5$	V
		Suspend or 3-state mode	<u>[1]</u> –0.5	+4.6	V
Io	output current	$V_O = 0 V \text{ to } V_{CC}$	[2] _	±50	mA
I <sub>CC</sub>	supply current	$I_{CC(A)}$ or $I_{CC(B)}$	-	100	mA
I <sub>GND</sub>	ground current		-100	-	mA
T <sub>stg</sub>	storage temperature		<b>–65</b>	+150	°C
P <sub>tot</sub>	total power dissipation	$T_{amb} = -40  ^{\circ}\text{C} \text{ to } +125  ^{\circ}\text{C};$			
		TSSOP48 package	<u>[4]</u> _	500	mW
		VFBGA56 package	<u>[5]</u> _	1000	mW
		HXQFN60U package	<u>[5]</u> _	1000	mW

<sup>[1]</sup> The minimum input voltage ratings and output voltage ratings may be exceeded if the input and output current ratings are observed.

# 8. Recommended operating conditions

Table 5. Recommended operating conditions

Symbol	Parameter	Conditions	Min	Max	Unit
$V_{CC(A)}$	supply voltage A		0.8	3.6	V
$V_{CC(B)}$	supply voltage B		0.8	3.6	V
VI	input voltage		0	3.6	V
Vo	output voltage	Active mode	<u>[1]</u> 0	$V_{CCO}$	V
		Suspend or 3-state mode	0	3.6	V
T <sub>amb</sub>	ambient temperature		-40	+125	°C
$\Delta t/\Delta V$	input transition rise and fall rate	$V_{CCI} = 0.8 \text{ V to } 3.6 \text{ V}$	[2] _	5	ns/V

<sup>[1]</sup>  $V_{CCO}$  is the supply voltage associated with the output port.

<sup>[2]</sup> V<sub>CCO</sub> is the supply voltage associated with the output port.

<sup>[3]</sup>  $V_{CCO} + 0.5 \text{ V}$  should not exceed 4.6 V.

<sup>[4]</sup> Above 60 °C the value of  $P_{tot}$  derates linearly with 5.5 mW/K.

<sup>[5]</sup> Above 70 °C the value of  $P_{tot}$  derates linearly with 1.8 mW/K.

<sup>[2]</sup> V<sub>CCI</sub> is the supply voltage associated with the input port.

#### 9. Static characteristics

Table 6. Typical static characteristics at  $T_{amb} = 25 \, ^{\circ}C_{-}^{[1][2]}$ 

At recommended operating conditions; voltages are referenced to GND (ground = 0 V).

	, ,				
Parameter	Conditions	Min	Тур	Max	Unit
HIGH-level output voltage	$V_I = V_{IH}$ or $V_{IL}$				
	$I_{O} = -1.5 \text{ mA}; \ V_{CC(A)} = V_{CC(B)} = 0.8 \ V$	-	0.69	-	V
LOW-level output voltage	$V_I = V_{IH}$ or $V_{IL}$				
	$I_O = 1.5 \text{ mA}; V_{CC(A)} = V_{CC(B)} = 0.8 \text{ V}$	-	0.07	-	V
input leakage current	nDIR, n $\overline{OE}$ input; V <sub>I</sub> = 0 V or 3.6 V; V <sub>CC(A)</sub> = V <sub>CC(B)</sub> = 0.8 V to 3.6 V	-	±0.025	±0.25	μА
bus hold LOW current	A or B port; $V_I = 0.42 \text{ V}$ ; $V_{CC(A)} = V_{CC(B)} = 1.2 \text{ V}$	[3]	26	-	μΑ
bus hold HIGH current	A or B port; $V_I = 0.78 \text{ V}$ ; $V_{CC(A)} = V_{CC(B)} = 1.2 \text{ V}$	[4] _	-24	-	μΑ
bus hold LOW overdrive current	A or B port; $V_{CC(A)} = V_{CC(B)} = 1.2 \text{ V}$	<u>[5]</u> _	27	-	μА
bus hold HIGH overdrive current	A or B port; $V_{CC(A)} = V_{CC(B)} = 1.2 \text{ V}$	<u>[6]</u> _	-26	-	μА
OFF-state output current	A or B port; $V_O = 0 \text{ V or } V_{CCO}$ ; $V_{CC(A)} = V_{CC(B)} = 3.6 \text{ V}$	<u>[7]</u> -	±0.5	±2.5	μА
	suspend mode A port; $V_O = 0 \text{ V or } V_{CCO}$ ; $V_{CC(A)} = 3.6 \text{ V}$ ; $V_{CC(B)} = 0 \text{ V}$	<u>[7]</u> -	±0.5	±2.5	μА
	suspend mode B port; $V_O = 0 \text{ V or } V_{CCO}$ ; $V_{CC(A)} = 0 \text{ V}$ ; $V_{CC(B)} = 3.6 \text{ V}$	<u>[7]</u> _	±0.5	±2.5	μΑ
power-off leakage current	A port; $V_1$ or $V_0 = 0$ V to 3.6 V; $V_{CC(A)} = 0$ V; $V_{CC(B)} = 0.8$ V to 3.6 V	-	±0.1	±1	μА
	B port; $V_1$ or $V_0 = 0$ V to 3.6 V; $V_{CC(B)} = 0$ V; $V_{CC(A)} = 0.8$ V to 3.6 V	-	±0.1	±1	μА
input capacitance	nDIR, n $\overline{OE}$ input; V <sub>I</sub> = 0 V or 3.3 V; V <sub>CC(A)</sub> = V <sub>CC(B)</sub> = 3.3 V	-	2.0	-	pF
input/output capacitance	A and B port; $V_O = 3.3 \text{ V or } 0 \text{ V};$ $V_{CC(A)} = V_{CC(B)} = 3.3 \text{ V}$	-	4.5	-	pF
	LOW-level output voltage  input leakage current  bus hold LOW current bus hold HIGH current bus hold LOW overdrive current bus hold HIGH overdrive current  OFF-state output current  power-off leakage current  input capacitance	$\label{eq:high-level output voltage} HIGH-level output voltage \\ LOW-level output voltage \\ LOW-level output voltage \\ LOW-level output voltage \\ V_1 = V_{IH} \text{ or } V_{IL} \\ I_O = 1.5 \text{ mA; } V_{CC(A)} = V_{CC(B)} = 0.8 \text{ V} \\ \text{input leakage current} \\ \text{nDIR, } \overline{\text{nOE}} \text{ input; } V_1 = 0 \text{ V or } 3.6 \text{ V; } \\ V_{CC(A)} = V_{CC(B)} = 0.8 \text{ V to } 3.6 \text{ V} \\ \text{bus hold LOW current} \\ \text{A or B port; } V_1 = 0.42 \text{ V; } V_{CC(A)} = V_{CC(B)} = 1.2 \text{ V} \\ \text{bus hold LOW overdrive current} \\ \text{bus hold HIGH overdrive current} \\ \text{DSF-state output current} \\ \text{OFF-state output current} \\ \text{OFF-state output current} \\ \text{A or B port; } V_{CC(A)} = V_{CC(B)} = 1.2 \text{ V} \\ \text{suspend mode A port; } V_O = 0 \text{ V or } V_{CCO;} \\ V_{CC(A)} = V_{CC(B)} = 3.6 \text{ V} \\ \text{suspend mode B port; } V_O = 0 \text{ V or } V_{CCO;} \\ V_{CC(A)} = 0 \text{ V; } V_{CC(B)} = 3.6 \text{ V} \\ \text{suspend mode B port; } V_O = 0 \text{ V or } V_{CCO;} \\ V_{CC(A)} = 0 \text{ V; } V_{CC(B)} = 0.8 \text{ V to } 3.6 \text{ V;} \\ V_{CC(A)} = 0 \text{ V; } V_{CC(B)} = 0.8 \text{ V to } 3.6 \text{ V;} \\ V_{CC(A)} = 0 \text{ V; } V_{CC(B)} = 0.8 \text{ V to } 3.6 \text{ V;} \\ V_{CC(B)} = 0 \text{ V; } V_{CC(A)} = 0.8 \text{ V to } 3.6 \text{ V;} \\ V_{CC(B)} = 0 \text{ V; } V_{CC(B)} = 3.3 \text{ V to } 3.3 \text{ V;} \\ V_{CC(A)} = V_{CC(B)} = 3.3 \text{ V or } 0.8 \text{ V to } 3.3 \text{ V;} \\ V_{CC(A)} = V_{CC(B)} = 3.3 \text{ V or } 0.8 \text{ V to } 0.8 \text{ V or } 0.8 \text{ V;} \\ V_{CC(A)} = V_{CC(B)} = 3.3 \text{ V or } 0.8 \text{ V or } 0.8 \text{ V;} \\ V_{CC(A)} = V_{CC(B)} = 3.3 \text{ V or } 0.8 \text{ V;} \\ V_{CC(A)} = V_{CC(B)} = 3.3 \text{ V or } 0.8 \text{ V;} \\ V_{CC(A)} = V_{CC(B)} = 3.3 \text{ V or } 0.8 \text{ V;} \\ V_{CC(A)} = V_{CC(B)} = 3.3 \text{ V or } 0.8 \text{ V;} \\ V_{CC(A)} = V_{CC(B)} = 3.3 \text{ V or } 0.8 \text{ V;} \\ V_{CC(A)} = V_{CC(B)} = 3.3 \text{ V or } 0.8 \text{ V;} \\ V_{CC(A)} = V_{CC(B)} = 3.3 \text{ V or } 0.8 \text{ V;} \\ V_{CC(A)} = V_{CC(B)} = 3.3 \text{ V or } 0.8 \text{ V;} \\ V_{CC(A)} = V_{CC(B)} = 3.3 \text{ V or } 0.8 \text{ V;} \\ V_{CC(A)} = V_{CC(B)} = 3.3 \text{ V or } 0.8 \text{ V;} \\ V_{CC(A)} = V_{CC(B)} = 3.3 \text{ V or } 0.8 \text{ V;} \\ V_{CC(A)} = V_{CC(B)} = 3.3 \text{ V or } 0$	$ \begin{tabular}{ll} HIGH-level output voltage & V_1 = V_{IH} \ or \ V_{IL} & I_0 = -1.5 \ mA; \ V_{CC(A)} = V_{CC(B)} = 0.8 \ V & - \\ \hline LOW-level output voltage & V_1 = V_{IH} \ or \ V_{IL} & I_0 = 1.5 \ mA; \ V_{CC(A)} = V_{CC(B)} = 0.8 \ V & - \\ \hline Input leakage current & nDIR, \ n\overline{OE} \ input; \ V_1 = 0 \ V \ or \ 3.6 \ V; \ V_{CC(A)} = V_{CC(B)} = 0.8 \ V \ to \ 3.6 \ V \\ \hline bus hold LOW current & A \ or B \ port; \ V_1 = 0.42 \ V; \ V_{CC(A)} = V_{CC(B)} = 1.2 \ V & 3 \ - \\ \hline bus hold HIGH \ current & A \ or B \ port; \ V_1 = 0.78 \ V; \ V_{CC(A)} = V_{CC(B)} = 1.2 \ V & 4 \ - \\ \hline bus hold LOW \ overdrive \ current & A \ or B \ port; \ V_{CC(A)} = V_{CC(B)} = 1.2 \ V & 5 \ - \\ \hline bus hold HIGH \ overdrive \ current & A \ or B \ port; \ V_{CC(A)} = V_{CC(B)} = 1.2 \ V & 5 \ - \\ \hline V_{CC(A)} = V_{CC(B)} = 3.6 \ V & 5 \ - \\ \hline V_{CC(A)} = V_{CC(B)} = 3.6 \ V & 5 \ - \\ \hline V_{CC(A)} = V_{CC(B)} = 3.6 \ V & 5 \ - \\ \hline V_{CC(A)} = 0 \ V; \ V_{CC(B)} = 0 \ V \ or V_{CCO}; & 7 \ - \\ \hline V_{CC(A)} = 0 \ V; \ V_{CC(B)} = 0.8 \ V \ to \ 3.6 \ V; & - \\ \hline V_{CC(A)} = 0 \ V; \ V_{CC(B)} = 0.8 \ V \ to \ 3.6 \ V; & - \\ \hline Input \ capacitance & DIR, \ n\overline{OE} \ input; \ V_1 = 0 \ V \ or \ 3.3 \ V; & - \\ \hline Input/output \ capacitance & A \ and \ B \ port; \ V_0 = 3.3 \ V \ or \ 0 \ V; & - \\ \hline \end{tabular}$	$ \begin{array}{llllllllllllllllllllllllllllllllllll$	$\begin{tabular}{ l l l l l l l l l l l l l l l l l l l$

<sup>[1]</sup>  $V_{CCO}$  is the supply voltage associated with the output port.

<sup>[2]</sup> V<sub>CCI</sub> is the supply voltage associated with the data input port.

<sup>[3]</sup> The bus hold circuit can sink at least the minimum low sustaining current at V<sub>IL</sub> max. I<sub>BHL</sub> should be measured after lowering V<sub>I</sub> to GND and then raising it to V<sub>IL</sub> max.

<sup>[4]</sup> The bus hold circuit can source at least the minimum high sustaining current at V<sub>IH</sub> min. I<sub>BHH</sub> should be measured after raising V<sub>I</sub> to V<sub>CC</sub> and then lowering it to V<sub>IH</sub> min.

<sup>[5]</sup> An external driver must source at least I<sub>BHLO</sub> to switch this node from LOW to HIGH.

<sup>[6]</sup> An external driver must sink at least I<sub>BHHO</sub> to switch this node from HIGH to LOW.

<sup>[7]</sup> For I/O ports, the parameter I<sub>OZ</sub> includes the input leakage current.

Table 7. Static characteristics [1][2]

At recommended operating conditions; voltages are referenced to GND (ground = 0 V).

Symbol	Parameter	Conditions	-40 °C t	o +85 °C	-40 °C to	+125 °C	Uni
			Min	Max	Min	Max	
/ <sub>IH</sub>	HIGH-level	data input			1	1	
	input voltage	V <sub>CCI</sub> = 0.8 V	0.70V <sub>CCI</sub>	-	0.70V <sub>CCI</sub>	-	٧
		V <sub>CCI</sub> = 1.1 V to 1.95 V	0.65V <sub>CCI</sub>	-	0.65V <sub>CCI</sub>	-	V
		V <sub>CCI</sub> = 2.3 V to 2.7 V	1.6	-	1.6	-	V
		V <sub>CCI</sub> = 3.0 V to 3.6 V	2	-	2	-	V
		nDIR, nOE input					
		V <sub>CC(A)</sub> = 0.8 V	0.70V <sub>CC(A)</sub>	-	0.70V <sub>CC(A)</sub>	-	V
		V <sub>CC(A)</sub> = 1.1 V to 1.95 V	0.65V <sub>CC(A)</sub>	-	0.65V <sub>CC(A)</sub>	-	V
		$V_{CC(A)} = 2.3 \text{ V to } 2.7 \text{ V}$	1.6	-	1.6	-	V
		$V_{CC(A)} = 3.0 \text{ V to } 3.6 \text{ V}$	2	-	2	-	V
, IL	LOW-level	data input					
	input voltage	V <sub>CCI</sub> = 0.8 V	-	0.30V <sub>CCI</sub>	-	0.30V <sub>CCI</sub>	V
		V <sub>CCI</sub> = 1.1 V to 1.95 V	-	0.35V <sub>CCI</sub>	-	0.35V <sub>CCI</sub>	V
		V <sub>CCI</sub> = 2.3 V to 2.7 V	-	0.7	-	0.7	V
		V <sub>CCI</sub> = 3.0 V to 3.6 V	-	0.8	-	0.8	V
		nDIR, nOE input					
		V <sub>CC(A)</sub> = 0.8 V	-	0.30V <sub>CC(A)</sub>	-	0.30V <sub>CC(A)</sub>	V
		V <sub>CC(A)</sub> = 1.1 V to 1.95 V	-	0.35V <sub>CC(A)</sub>	-	0.35V <sub>CC(A)</sub>	
		$V_{CC(A)} = 2.3 \text{ V to } 2.7 \text{ V}$	-	0.7	-	0.7	V
		V <sub>CC(A)</sub> = 3.0 V to 3.6 V	-	0.8	-	0.8	V
он	HIGH-level	$V_I = V_{IH}$ or $V_{IL}$					
	output voltage	$I_O = -100 \mu A;$ $V_{CC(A)} = V_{CC(B)} = 0.8 \text{ V to } 3.6 \text{ V}$	V <sub>CCO</sub> - 0.1	-	V <sub>CCO</sub> - 0.1	-	V
		$I_{O} = -3 \text{ mA}; V_{CC(A)} = V_{CC(B)} = 1.1 \text{ V}$	0.85	-	0.85	-	V
		$I_O = -6 \text{ mA}; V_{CC(A)} = V_{CC(B)} = 1.4 \text{ V}$	1.05	-	1.05	-	V
		$I_O = -8 \text{ mA};$ $V_{CC(A)} = V_{CC(B)} = 1.65 \text{ V}$	1.2	-	1.2	-	V
		$I_{O} = -9 \text{ mA}; V_{CC(A)} = V_{CC(B)} = 2.3 \text{ V}$	1.75	-	1.75	-	V
		$I_O = -12 \text{ mA};$ $V_{CC(A)} = V_{CC(B)} = 3.0 \text{ V}$	2.3	-	2.3	-	V
OL	LOW-level	$V_I = V_{IH}$ or $V_{IL}$					
	output voltage	$I_{O}$ = 100 $\mu$ A; $V_{CC(A)} = V_{CC(B)} = 0.8 \text{ V to } 3.6 \text{ V}$	-	0.1	-	0.1	V
		$I_{O} = 3 \text{ mA}; V_{CC(A)} = V_{CC(B)} = 1.1 \text{ V}$	-	0.25	-	0.25	V
		$I_{O} = 6 \text{ mA}; V_{CC(A)} = V_{CC(B)} = 1.4 \text{ V}$	-	0.35	-	0.35	V
		$I_{O} = 8 \text{ mA}; V_{CC(A)} = V_{CC(B)} = 1.65 \text{ V}$	-	0.45	-	0.45	٧
		$I_O = 9 \text{ mA}; V_{CC(A)} = V_{CC(B)} = 2.3 \text{ V}$	-	0.55	-	0.55	٧
		$I_{O} = 12 \text{ mA}; V_{CC(A)} = V_{CC(B)} = 3.0 \text{ V}$	-	0.7	-	0.7	V
	input leakage current	nDIR, n $\overline{OE}$ input; V <sub>I</sub> = 0 V or 3.6 V; V <sub>CC(A)</sub> = V <sub>CC(B)</sub> = 0.8 V to 3.6 V	-	±1	-	±5	μΑ

74AVCH16T245\_2

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 Table 7.
 Static characteristics ...continueo

At recommended operating conditions; voltages are referenced to GND (ground = 0 V).

Symbol	Parameter	Conditions		-40 °C t	o +85 °C	-40 °C to	+125 °C	Unit
				Min	Max	Min	Max	
I <sub>BHL</sub>	bus hold	A or B port	[3]					
	LOW current	$V_I = 0.49 \text{ V}; V_{CC(A)} = V_{CC(B)} = 1.4 \text{ V}$		15	-	15	-	μΑ
		$V_I = 0.58 \text{ V};$ $V_{CC(A)} = V_{CC(B)} = 1.65 \text{ V}$		25	-	25	-	μΑ
		$V_{I} = 0.70 \text{ V}; V_{CC(A)} = V_{CC(B)} = 2.3 \text{ V}$		45	-	45	-	μΑ
		$V_{I} = 0.80 \text{ V}; V_{CC(A)} = V_{CC(B)} = 3.0 \text{ V}$		100	-	90	-	μΑ
I <sub>BHH</sub>	bus hold	A or B port	<u>[4]</u>					
	HIGH current	$V_I = 0.91 \text{ V}; V_{CC(A)} = V_{CC(B)} = 1.4 \text{ V}$		-15	-	-15	-	μΑ
		$V_I = 1.07 \text{ V};$ $V_{CC(A)} = V_{CC(B)} = 1.65 \text{ V}$		-25	-	<b>–25</b>	-	μΑ
		$V_I = 1.60 \text{ V}; V_{CC(A)} = V_{CC(B)} = 2.3 \text{ V}$		<b>-45</b>	-	-45	-	μΑ
		$V_I = 2.00 \text{ V}; V_{CC(A)} = V_{CC(B)} = 3.0 \text{ V}$		-100	-	-100	-	μΑ
I <sub>BHLO</sub>	bus hold	A or B port	<u>[5]</u>					
	LOW overdrive	$V_{CC(A)} = V_{CC(B)} = 1.6 \text{ V}$		125	-	125	-	μΑ
	current	$V_{CC(A)} = V_{CC(B)} = 1.95 \text{ V}$		200	-	200	-	μΑ
		$V_{CC(A)} = V_{CC(B)} = 2.7 \text{ V}$		300	-	300	-	μΑ
		$V_{CC(A)} = V_{CC(B)} = 3.6 \text{ V}$		500	-	500	-	μΑ
$I_{BHHO}$	bus hold	A or B port	[6]					
	HIGH overdrive	$V_{CC(A)} = V_{CC(B)} = 1.6 \text{ V}$		-125	-	-125	-	μΑ
	current	$V_{CC(A)} = V_{CC(B)} = 1.95 \text{ V}$		-200	-	-200	-	μΑ
		$V_{CC(A)} = V_{CC(B)} = 2.7 \text{ V}$		-300	-	-300	-	μΑ
		$V_{CC(A)} = V_{CC(B)} = 3.6 \text{ V}$		-500	-	-500	-	μΑ
l <sub>OZ</sub>	OFF-state output	A or B port; $V_O = 0 \text{ V or } V_{CCO}$ ; $V_{CC(A)} = V_{CC(B)} = 3.6 \text{ V}$	<u>[7]</u>	-	±5	-	±30	μА
	current	suspend mode A port; $V_O = 0 \text{ V or } V_{CC(A)}$ ; $V_{CC(B)} = 3.6 \text{ V}$ ; $V_{CC(B)} = 0 \text{ V}$	<u>[7]</u>	-	±5	-	±30	μΑ
		suspend mode B port; $V_O = 0 \text{ V or } V_{CC(A)}$ ; $V_{CC(A)} = 0 \text{ V}$ ; $V_{CC(B)} = 3.6 \text{ V}$	[7]	-	±5	-	±30	μА
I <sub>OFF</sub>	power-off leakage	A port; $V_1$ or $V_0 = 0$ V to 3.6 V; $V_{CC(A)} = 0$ V; $V_{CC(B)} = 0.8$ V to 3.6 V		-	±5	-	±30	μΑ
	current	B port; $V_1$ or $V_0 = 0$ V to 3.6 V; $V_{CC(B)} = 0$ V; $V_{CC(A)} = 0.8$ V to 3.6 V		-	±5	-	±30	μΑ

Table 7. Static characteristics ...continued[1][2]

At recommended operating conditions; voltages are referenced to GND (ground = 0 V).

Symbol	Parameter	Conditions	–40 °C t	o +85 °C	–40 °C to	+125 °C	Unit	
			Min	Max	Min	Max		
I <sub>CC</sub>	supply	A port; $V_I = 0 \text{ V or } V_{CCI}$ ; $I_O = 0 \text{ A}$	'		1			
	current	$V_{CC(A)} = 0.8 \text{ V to } 3.6 \text{ V};$ $V_{CC(B)} = 0.8 \text{ V to } 3.6 \text{ V}$	-	30	-	125	μА	
		$V_{CC(A)} = 1.1 \text{ V to } 3.6 \text{ V};$ $V_{CC(B)} = 1.1 \text{ V to } 3.6 \text{ V}$	-	25	-	100	μА	
		$V_{CC(A)} = 3.6 \text{ V}; V_{CC(B)} = 0 \text{ V}$	-	25	-	100	μΑ	
		$V_{CC(A)} = 0 \text{ V}; V_{CC(B)} = 3.6 \text{ V}$	-5	-	-20	-	μΑ	
		B port; $V_I = 0 \text{ V or } V_{CCI}$ ; $I_O = 0 \text{ A}$						
		$V_{CC(A)} = 0.8 \text{ V to } 3.6 \text{ V};$ $V_{CC(B)} = 0.8 \text{ V to } 3.6 \text{ V}$	-	30	-	125	μА	
				$V_{CC(A)} = 1.1 \text{ V to } 3.6 \text{ V};$ $V_{CC(B)} = 1.1 \text{ V to } 3.6 \text{ V}$	-	25	-	100
		$V_{CC(A)} = 3.6 \text{ V}; V_{CC(B)} = 0 \text{ V}$	-5	-	-20	-	μΑ	
		$V_{CC(A)} = 0 \text{ V}; V_{CC(B)} = 3.6 \text{ V}$	-	25	-	100	μΑ	
		A plus B port ( $I_{CC(A)} + I_{CC(B)}$ ); $I_O = 0$ A; $V_I = 0$ V or $V_{CCI}$ ; $V_{CC(A)} = 0.8$ V to 3.6 V; $V_{CC(B)} = 0.8$ V to 3.6 V	-	55	-	185	μΑ	
		A plus B port ( $I_{CC(A)} + I_{CC(B)}$ ); $I_O = 0$ A; $V_I = 0$ V or $V_{CCI}$ ; $V_{CC(A)} = 1.1$ V to 3.6 V; $V_{CC(B)} = 1.1$ V to 3.6 V	-	45	-	150	μА	

- [1] V<sub>CCO</sub> is the supply voltage associated with the output port.
- [2] V<sub>CCI</sub> is the supply voltage associated with the data input port.
- [3] The bus hold circuit can sink at least the minimum low sustaining current at V<sub>IL</sub> max. I<sub>BHL</sub> should be measured after lowering V<sub>I</sub> to GND and then raising it to V<sub>IL</sub> max.
- [4] The bus hold circuit can source at least the minimum high sustaining current at V<sub>IH</sub> min. I<sub>BHH</sub> should be measured after raising V<sub>I</sub> to V<sub>CC</sub> and then lowering it to V<sub>IH</sub> min.
- [5] An external driver must source at least I<sub>BHLO</sub> to switch this node from LOW to HIGH.
- [6] An external driver must sink at least I<sub>BHHO</sub> to switch this node from HIGH to LOW.
- [7] For I/O ports, the parameter  $I_{OZ}$  includes the input leakage current.

Table 8. Typical total supply current  $(I_{CC(A)} + I_{CC(B)})$ 

V <sub>CC(A)</sub>	V <sub>CC(B)</sub>	V <sub>CC(B)</sub>						
	0 V	0.8 V	1.2 V	1.5 V	1.8 V	2.5 V	3.3 V	
0 V	0	0.1	0.1	0.1	0.1	0.1	0.1	μΑ
0.8 V	0.1	0.1	0.1	0.1	0.1	0.3	1.6	μΑ
1.2 V	0.1	0.1	0.1	0.1	0.1	0.1	0.8	μΑ
1.5 V	0.1	0.1	0.1	0.1	0.1	0.1	0.4	μΑ
1.8 V	0.1	0.1	0.1	0.1	0.1	0.1	0.2	μΑ
2.5 V	0.1	0.3	0.1	0.1	0.1	0.1	0.1	μΑ
3.3 V	0.1	1.6	0.8	0.4	0.2	0.1	0.1	μΑ

74AVCH16T245\_2

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# 10. Dynamic characteristics

Table 9. Typical power dissipation capacitance at  $V_{CC(A)} = V_{CC(B)}$  and  $T_{amb} = 25 \, ^{\circ}C$  [1][2] Voltages are referenced to GND (ground = 0 V).

Symbol	Parameter	Conditions			V <sub>CC(A)</sub> =	V <sub>CC(B)</sub>			Unit
			0.8 V	1.2 V	1.5 V	1.8 V	2.5 V	3.3 V	
$C_{PD}$	power dissipation capacitance	A port: (direction nAn to nBn); output enabled	0.2	0.2	0.2	0.2	0.3	0.4	pF
		A port: (direction nAn to nBn); output disabled	0.2	0.2	0.2	0.2	0.3	0.4	pF
		A port: (direction nBn to nAn); output enabled	9	9.7	9.8	10.3	11.7	13.7	pF
		A port: (direction nBn to nAn); output disabled	0.6	0.6	0.6	0.7	0.7	0.7	pF
		B port: (direction nAn to nBn); output enabled	9	9.7	9.8	10.3	11.7	13.7	pF
		B port: (direction nAn to nBn); output disabled	0.6	0.6	0.6	0.7	0.7	0.7	pF
		B port: (direction nBn to nAn); output enabled	0.2	0.2	0.2	0.2	0.3	0.4	pF
		B port: (direction nBn to nAn); output disabled	0.2	0.2	0.2	0.2	0.3	0.4	pF

<sup>[1]</sup>  $C_{PD}$  is used to determine the dynamic power dissipation ( $P_D$  in  $\mu W$ ).

 $P_D = C_{PD} \times V_{CC}^2 \times f_i \times N + \Sigma (C_L \times V_{CC}^2 \times f_o)$  where:

f<sub>i</sub> = input frequency in MHz;

f<sub>o</sub> = output frequency in MHz;

C<sub>L</sub> = load capacitance in pF;

V<sub>CC</sub> = supply voltage in V;

N = number of inputs switching;

 $\Sigma(C_L \times V_{CC}{}^2 \times f_o)$  = sum of the outputs.

[2]  $f_i$  = 10 MHz;  $V_I$  = GND to  $V_{CC}$ ;  $t_f$  =  $t_f$  = 1 ns;  $C_L$  = 0 pF;  $R_L$  =  $\infty$   $\Omega$ .

Table 10. Typical dynamic characteristics at  $V_{CC(A)} = 0.8 \text{ V}$  and  $T_{amb} = 25 ^{\circ}\text{C}$  [1]

Voltages are referenced to GND (ground = 0 V); for test circuit see Figure 8; for wave forms see Figure 6 and Figure 7

Symbol	Parameter	Conditions	V <sub>CC(B)</sub>						Unit
			0.8 V	1.2 V	1.5 V	1.8 V	2.5 V	3.3 V	
$t_{pd}$	propagation delay	nAn to nBn	14.4	7.0	6.2	6.0	5.9	6.0	ns
	nBn to nAn	14.4	12.4	12.1	11.9	11.8	11.8	ns	
t <sub>dis</sub>	disable time	nOE to nAn	16.2	16.2	16.2	16.2	16.2	16.2	ns
		nOE to nBn	17.6	10.0	9.0	9.1	8.7	9.3	ns
t <sub>en</sub>	enable time	nOE to nAn	21.9	21.9	21.9	21.9	21.9	21.9	ns
		nOE to nBn	22.2	11.1	9.8	9.4	9.4	9.6	ns

<sup>[1]</sup>  $t_{pd}$  is the same as  $t_{PLH}$  and  $t_{PHL}$ ;  $t_{dis}$  is the same as  $t_{PLZ}$  and  $t_{PHZ}$ ;  $t_{en}$  is the same as  $t_{PZL}$  and  $t_{PZH}$ .

Table 11. Typical dynamic characteristics at  $V_{CC(B)} = 0.8 \text{ V}$  and  $T_{amb} = 25 \,^{\circ}\text{C}$ 

Voltages are referenced to GND (ground = 0 V); for test circuit see Figure 8; for wave forms see Figure 6 and Figure 7

Symbol	Symbol Parameter Conditions				V <sub>CC(A)</sub>						
			0.8 V	1.2 V	1.5 V	1.8 V	2.5 V	3.3 V			
$t_{pd}$	propagation delay	nAn to nBn	14.4	12.4	12.1	11.9	11.8	11.8	ns		
		nBn to nAn	14.4	7.0	6.2	6.0	5.9	6.0	ns		
$t_{dis}$	disable time	nOE to nAn	16.2	5.9	4.4	4.2	3.1	3.5	ns		
		nOE to nBn	17.6	14.2	13.7	13.6	13.3	13.1	ns		
t <sub>en</sub>	enable time	nOE to nAn	21.9	6.4	4.4	3.5	2.6	2.3	ns		
		nOE to nBn	22.2	17.7	17.2	17.0	16.8	16.7	ns		

<sup>[1]</sup>  $t_{pd}$  is the same as  $t_{PLH}$  and  $t_{PHL}$ ;  $t_{dis}$  is the same as  $t_{PLZ}$  and  $t_{PHZ}$ ;  $t_{en}$  is the same as  $t_{PZL}$  and  $t_{PZH}$ .

Table 12. Dynamic characteristics for temperature range  $-40~^{\circ}\text{C}$  to  $+85~^{\circ}\text{C}$  [1]

Voltages are referenced to GND (ground = 0 V); for test circuit see Figure 8; for wave forms see Figure 6 and Figure 7.

Symbol	Parameter	Conditions					_	C(B)					Unit
			1.2 V	± 0.1 V	1.5 V	± 0.1 V	1.8 V ±	± 0.15 V	2.5 V	± 0.2 V	3.3 V	± 0.3 V	
			Min	Max	Min	Max	Min	Max	Min	Max	Min	Max	
V <sub>CC(A)</sub> =	1.1 V to 1.3 V	•						'					
t <sub>pd</sub>	propagation	nAn to nBn	0.5	9.2	0.5	6.9	0.5	6.0	0.5	5.1	0.5	4.9	ns
	delay	nBn to nAn	0.5	9.2	0.5	8.7	0.5	8.5	0.5	8.2	0.5	8.0	ns
t <sub>dis</sub>	disable time	nOE to nAn	1.5	11.6	1.5	11.6	1.5	11.6	1.5	11.6	1.5	11.6	ns
		n <del>OE</del> to nBn	1.5	12.5	1.5	9.7	1.5	9.5	1.0	8.1	1.0	8.9	ns
t <sub>en</sub>	enable time	n <del>OE</del> to nAn	1.0	14.5	1.0	14.5	1.0	14.5	1.0	14.5	1.0	14.5	ns
		nOE to nBn	1.1	14.9	1.1	11.0	1.1	9.6	1.0	8.1	1.0	7.7	ns
V <sub>CC(A)</sub> =	1.4 V to 1.6 V												
t <sub>pd</sub>	propagation	nAn to nBn	0.5	8.7	0.5	6.2	0.5	5.2	0.5	4.1	0.5	3.7	ns
	delay	nBn to nAn	0.5	6.9	0.5	6.2	0.5	5.9	0.5	5.6	0.5	5.5	ns
t <sub>dis</sub>	disable time	nOE to nAn	1.5	9.1	1.5	9.1	1.5	9.1	1.5	9.1	1.5	9.1	ns
		nOE to nBn	1.5	11.4	1.5	8.7	1.5	7.5	1.0	6.5	1.0	6.3	ns
t <sub>en</sub>	enable time	nOE to nAn	1.0	10.1	1.0	10.1	1.0	10.1	1.0	10.1	1.0	10.1	ns
		nOE to nBn	1.0	13.5	1.0	10.1	0.5	8.1	0.5	5.9	0.5	5.2	ns
V <sub>CC(A)</sub> =	1.65 V to 1.95	V											
t <sub>pd</sub>	propagation delay	nAn to nBn	0.5	8.5	0.5	5.9	0.5	4.8	0.5	3.7	0.5	3.3	ns
		nBn to nAn	0.5	6.0	0.5	5.2	0.5	4.8	0.5	4.5	0.5	4.4	ns
$t_{\text{dis}}$	disable time	nOE to nAn	1.5	7.7	1.5	7.7	1.5	7.7	1.5	7.7	1.5	7.7	ns
		nOE to nBn	1.5	11.1	1.5	8.4	1.5	7.1	1.0	5.9	1.0	5.7	ns
t <sub>en</sub>	enable time	nOE to nAn	1.0	7.8	1.0	7.8	1.0	7.8	1.0	7.8	1.0	7.8	ns
		nOE to nBn	1.0	13.0	1.0	9.2	0.5	7.4	0.5	5.3	0.5	4.5	ns
$V_{CC(A)} =$	2.3 V to 2.7 V												
$t_{pd}$	propagation	nAn to nBn	0.5	8.2	0.5	5.6	0.5	4.6	0.5	3.3	0.5	2.8	ns
	delay	nBn to nAn	0.5	5.1	0.5	4.1	0.5	3.7	0.5	3.4	0.5	3.2	ns
$t_{\text{dis}}$	disable time	nOE to nAn	1.0	6.1	1.0	6.1	1.0	6.1	1.0	6.1	1.0	6.1	ns
		nOE to nBn	1.0	10.6	1.0	7.9	1.0	6.6	1.0	6.1	1.0	5.2	ns
t <sub>en</sub>	enable time	nOE to nAn	0.5	5.3	0.5	5.3	0.5	5.3	0.5	5.3	0.5	5.3	ns
		nOE to nBn	0.5	12.5	0.5	9.4	0.5	7.3	0.5	5.1	0.5	4.5	ns
$V_{CC(A)} =$	3.0 V to 3.6 V												
$t_{pd}$	propagation	nAn to nBn	0.5	8.0	0.5	5.5	0.5	4.4	0.5	3.2	0.5	2.7	ns
	delay	nBn to nAn	0.5	4.9	0.5	3.7	0.5	3.3	0.5	2.9	0.5	2.7	ns
$t_{\text{dis}}$	disable time	nOE to nAn	0.5	5.0	0.5	5.0	0.5	5.0	0.5	5.0	0.5	5.0	ns
		nOE to nBn	1.0	10.3	1.0	7.7	1.0	6.5	1.0	5.2	0.5	5.0	ns
t <sub>en</sub>	enable time	nOE to nAn	0.5	4.3	0.5	4.3	0.5	4.2	0.5	4.1	0.5	4.0	ns
		nOE to nBn	0.5	12.4	0.5	9.3	0.5	7.2	0.5	4.9	0.5	4.0	ns

<sup>[1]</sup>  $t_{pd}$  is the same as  $t_{PLH}$  and  $t_{PHL}$ ;  $t_{dis}$  is the same as  $t_{PLZ}$  and  $t_{PHZ}$ ;  $t_{en}$  is the same as  $t_{PZL}$  and  $t_{PZH}$ .

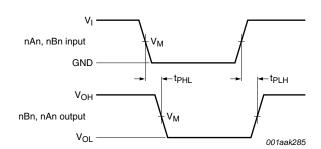
Table 13. Dynamic characteristics for temperature range  $-40~^{\circ}\text{C}$  to  $+125~^{\circ}\text{C}$  [1]

Voltages are referenced to GND (ground = 0 V); for test circuit see Figure 8; for wave forms see Figure 6 and Figure 7

Symbol	Parameter	Conditions					Vc	C(B)					Unit
			1.2 V	± 0.1 V	1.5 V	± 0.1 V	1.8 V ±	± 0.15 V	2.5 V	± 0.2 V	3.3 V	± 0.3 V	
			Min	Max	Min	Max	Min	Max	Min	Max	Min	Max	
V <sub>CC(A)</sub> =	1.1 V to 1.3 V	•	'	'	'	•	•	'			'	•	
t <sub>pd</sub>	propagation	nAn to nBn	0.5	10.2	0.5	7.6	0.5	6.6	0.5	5.7	0.5	5.4	ns
	delay	nBn to nAn	0.5	10.2	0.5	9.6	0.5	9.4	0.5	9.1	0.5	8.8	ns
t <sub>dis</sub>	disable time	n <del>OE</del> to nAn	1.5	12.8	1.5	12.8	1.5	12.8	1.5	12.8	1.5	12.8	ns
		$n\overline{OE}$ to $nBn$	1.5	13.8	1.5	10.7	1.5	10.5	1.0	9.0	1.5	9.8	ns
t <sub>en</sub> enable tir	enable time	n <del>OE</del> to nAn	1.0	16.0	1.0	16.0	1.0	16.0	1.0	16.0	1.0	16.0	ns
		nOE to nBn	1.1	16.4	1.1	12.1	1.1	10.6	1.0	9.0	1.0	8.5	ns
V <sub>CC(A)</sub> =	1.4 V to 1.6 V												
t <sub>pd</sub>	propagation	nAn to nBn	0.5	9.6	0.5	6.9	0.5	5.8	0.5	4.6	0.5	4.1	ns
	delay	nBn to nAn	0.5	7.6	0.5	6.9	0.5	6.5	0.5	6.2	0.5	6.1	ns
t <sub>dis</sub>	disable time	nOE to nAn	1.5	10.1	1.5	10.1	1.5	10.1	1.5	10.1	1.5	10.1	ns
		nOE to nBn	1.5	12.6	1.5	9.6	1.5	8.3	1.0	7.2	1.0	7.0	ns
t <sub>en</sub>	enable time	nOE to nAn	1.0	11.2	1.0	11.2	1.0	11.2	1.0	11.2	1.0	11.2	ns
		nOE to nBn	1.0	14.9	1.0	11.2	0.5	9.0	0.5	6.5	0.5	5.8	ns
$V_{CC(A)} =$	1.65 V to 1.95	V											
$t_{pd}$	propagation delay	nAn to nBn	0.5	9.4	0.5	6.5	0.5	5.3	0.5	4.1	0.5	3.7	ns
		nBn to nAn	0.5	6.6	0.5	5.8	0.5	5.3	0.5	5.0	0.5	4.9	ns
$t_{dis}$	disable time	nOE to nAn	1.5	8.5	1.5	8.5	1.5	8.5	1.5	8.5	1.5	8.5	ns
		nOE to nBn	1.5	12.3	1.5	9.3	1.5	7.9	1.0	6.5	1.0	6.3	ns
t <sub>en</sub>	enable time	nOE to nAn	1.0	8.6	1.0	8.6	1.0	8.6	1.0	8.6	1.0	8.6	ns
		nOE to nBn	1.0	14.3	1.0	10.2	0.5	8.2	0.5	5.9	0.5	5.0	ns
$V_{CC(A)} =$	2.3 V to 2.7 V												
$t_{pd}$	propagation	nAn to nBn	0.5	9.1	0.5	6.2	0.5	5.1	0.5	3.7	0.5	3.1	ns
	delay	nBn to nAn	0.5	5.7	0.5	4.6	0.5	4.1	0.5	3.8	0.5	3.6	ns
$t_{dis}$	disable time	nOE to nAn	1.0	6.8	1.0	6.8	1.0	6.8	1.0	6.8	1.0	6.8	ns
		nOE to nBn	1.0	11.7	1.0	8.7	1.0	7.3	1.0	6.8	1.0	5.8	ns
t <sub>en</sub>	enable time	nOE to nAn	0.5	5.9	0.5	5.9	0.5	5.9	0.5	5.9	0.5	5.9	ns
		nOE to nBn	0.5	13.8	0.5	10.4	0.5	8.1	0.5	5.7	0.5	5.0	ns
$V_{CC(A)} =$	3.0 V to 3.6 V												
$t_{pd}$	propagation	nAn to nBn	0.5	8.8	0.5	6.1	0.5	4.9	0.5	3.6	0.5	3.0	ns
	delay	nBn to nAn	0.5	5.4	0.5	4.1	0.5	3.7	0.5	3.2	0.5	3.0	ns
t <sub>dis</sub>	disable time	nOE to nAn	0.5	5.5	0.5	5.5	0.5	5.5	0.5	5.5	0.5	5.5	ns
		nOE to nBn	1.0	11.4	1.0	8.5	1.0	7.2	1.0	5.8	0.5	5.5	ns
t <sub>en</sub>	enable time	nOE to nAn	0.5	4.8	0.5	4.8	0.5	4.7	0.5	4.6	0.5	4.4	ns
		nOE to nBn	0.5	13.7	0.5	10.3	0.5	8.0	0.5	5.4	0.5	4.4	ns

<sup>[1]</sup>  $t_{pd}$  is the same as  $t_{PLH}$  and  $t_{PHL}$ ;  $t_{dis}$  is the same as  $t_{PLZ}$  and  $t_{PHZ}$ ;  $t_{en}$  is the same as  $t_{PZL}$  and  $t_{PZH}$ .

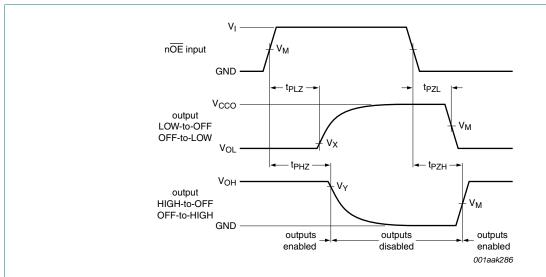
### 11. Waveforms



Measurement points are given in Table 14.

 $V_{\mbox{\scriptsize OL}}$  and  $V_{\mbox{\scriptsize OH}}$  are typical output voltage levels that occur with the output load.

Fig 6. The data input (nAn, nBn) to output (nBn, nAn) propagation delay times



Measurement points are given in Table 14.

V<sub>OL</sub> and V<sub>OH</sub> are typical output voltage levels that occur with the output load.

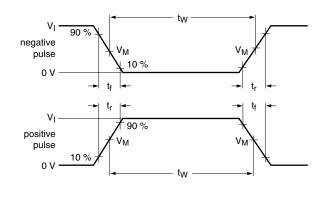
Fig 7. Enable and disable times

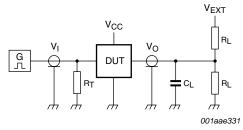
Table 14. Measurement points

Supply voltage	Input <sup>[1]</sup>	Output <sup>[2]</sup>		
V <sub>CC(A)</sub> , V <sub>CC(B)</sub>	V <sub>M</sub>	V <sub>M</sub>	V <sub>X</sub>	V <sub>Y</sub>
0.8 V to 1.6 V	0.5V <sub>CCI</sub>	0.5V <sub>CCO</sub>	V <sub>OL</sub> + 0.1 V	$V_{OH} - 0.1 V$
1.65 V to 2.7 V	0.5V <sub>CCI</sub>	0.5V <sub>CCO</sub>	V <sub>OL</sub> + 0.15 V	V <sub>OH</sub> – 0.15 V
3.0 V to 3.6 V	0.5V <sub>CCI</sub>	0.5V <sub>CCO</sub>	V <sub>OL</sub> + 0.3 V	V <sub>OH</sub> – 0.3 V

<sup>[1]</sup>  $V_{CCI}$  is the supply voltage associated with the data input port.

<sup>[2]</sup>  $V_{CCO}$  is the supply voltage associated with the output port.





Test data is given in Table 15.

R<sub>L</sub> = Load resistance.

C<sub>L</sub> = Load capacitance including jig and probe capacitance.

 $R_T$  = Termination resistance.

 $V_{\mathsf{EXT}}$  = External voltage for measuring switching times.

Fig 8. Load circuit for switching times

Table 15. Test data

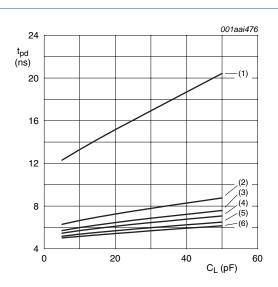
Supply voltage	Input		Load	Load		V <sub>EXT</sub>		
$V_{CC(A)}, V_{CC(B)}$	V <sub>I</sub> [1]	<b>∆t/</b> ∆ <b>V</b> [2]	C <sub>L</sub>	R <sub>L</sub>	t <sub>PLH</sub> , t <sub>PHL</sub>	t <sub>PZH</sub> , t <sub>PHZ</sub>	t <sub>PZL</sub> , t <sub>PLZ</sub> [3]	
0.8 V to 1.6 V	$V_{CCI}$	$\leq$ 1.0 ns/V	15 pF	2 kΩ	open	GND	2V <sub>CCO</sub>	
1.65 V to 2.7 V	V <sub>CCI</sub>	≤ 1.0 ns/V	15 pF	2 kΩ	open	GND	2V <sub>CCO</sub>	
3.0 V to 3.6 V	V <sub>CCI</sub>	≤ 1.0 ns/V	15 pF	2 kΩ	open	GND	2V <sub>CCO</sub>	

<sup>[1]</sup>  $V_{CCI}$  is the supply voltage associated with the data input port.

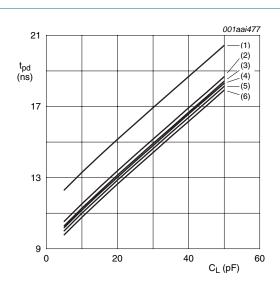
<sup>[2]</sup>  $dV/dt \ge 1.0 V/ns$ 

<sup>[3]</sup> V<sub>CCO</sub> is the supply voltage associated with the output port.

# 12. Typical propagation delay characteristics

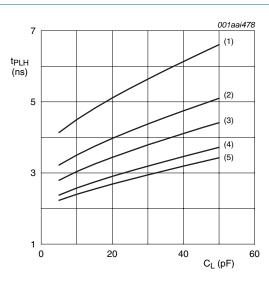


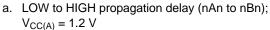
- a. Propagation delay (nAn to nBn); V<sub>CC(A)</sub> = 0.8 V
- (1)  $V_{CC(B)} = 0.8 \text{ V}.$
- (2)  $V_{CC(B)} = 1.2 \text{ V}.$
- (3)  $V_{CC(B)} = 1.5 \text{ V}.$
- (4)  $V_{CC(B)} = 1.8 \text{ V}.$
- (5)  $V_{CC(B)} = 2.5 \text{ V}.$
- (6)  $V_{CC(B)} = 3.3 \text{ V}.$

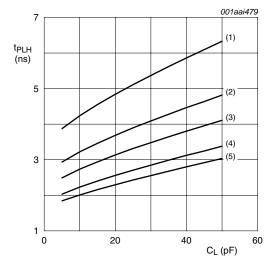


- b. Propagation delay (nAn to nBn);  $V_{CC(B)} = 0.8 \text{ V}$
- (1)  $V_{CC(A)} = 0.8 \text{ V}.$
- (2)  $V_{CC(A)} = 1.2 \text{ V}.$
- (3)  $V_{CC(A)} = 1.5 \text{ V}.$
- (4)  $V_{CC(A)} = 1.8 \text{ V}.$
- (5)  $V_{CC(A)} = 2.5 \text{ V}.$ (6)  $V_{CC(A)} = 3.3 \text{ V}.$

Fig 9. Typical propagation delay versus load capacitance; T<sub>amb</sub> = 25 °C





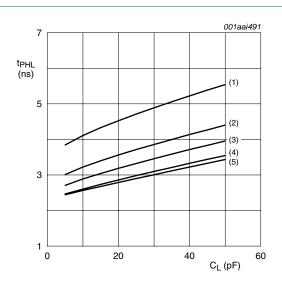


c. LOW to HIGH propagation delay (nAn to nBn);  $V_{CC(A)} = 1.5 \text{ V}$ 

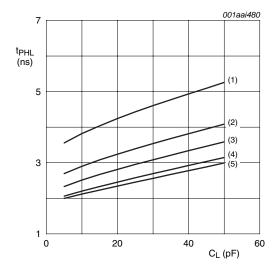


- (2)  $V_{CC(B)} = 1.5 \text{ V}.$
- (3)  $V_{CC(B)} = 1.8 \text{ V}.$
- (4)  $V_{CC(B)} = 2.5 \text{ V}.$
- (5)  $V_{CC(B)} = 3.3 \text{ V}.$

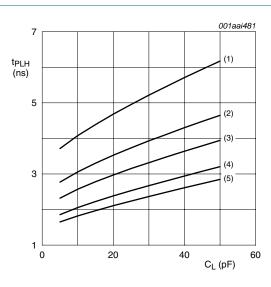
Fig 10. Typical propagation delay versus load capacitance;  $T_{amb}$  = 25 °C

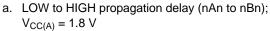


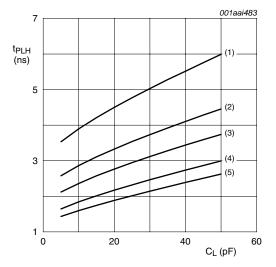
b. HIGH to LOW propagation delay (nAn to nBn);  $V_{CC(A)} = 1.2 \text{ V}$ 



d. HIGH to LOW propagation delay (nAn to nBn);  $V_{CC(A)} = 1.5 \text{ V}$ 



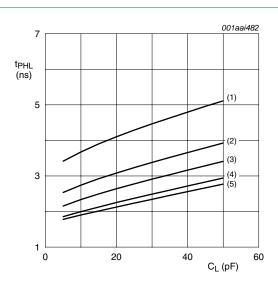




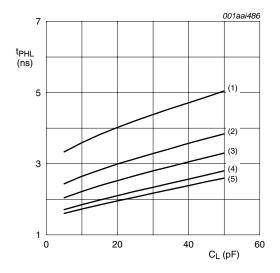
c. LOW to HIGH propagation delay (nAn to nBn);  $V_{CC(A)} = 2.5 \text{ V}$ 



- (2)  $V_{CC(B)} = 1.5 \text{ V}.$
- (3)  $V_{CC(B)} = 1.8 \text{ V}.$
- (4)  $V_{CC(B)} = 2.5 \text{ V}.$
- (5)  $V_{CC(B)} = 3.3 \text{ V}.$

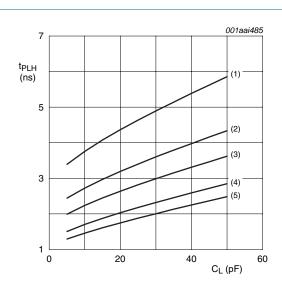


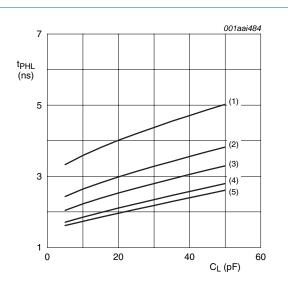
b. HIGH to LOW propagation delay (nAn to nBn);  $V_{CC(A)} = 1.8 \text{ V}$ 



d. HIGH to LOW propagation delay (nAn to nBn);  $V_{CC(A)} = 2.5 \text{ V}$ 







- a. LOW to HIGH propagation delay (nAn to nBn);  $V_{\text{CC(A)}} = 3.3 \text{ V}$
- b. HIGH to LOW propagation delay (nAn to nBn);  $V_{\text{CC(A)}} = 3.3 \text{ V}$

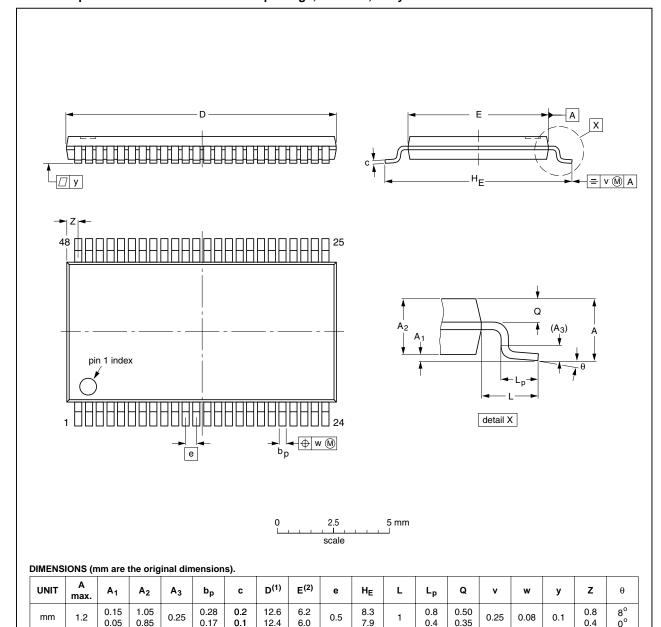
- (1)  $V_{CC(B)} = 1.2 \text{ V}.$
- (2)  $V_{CC(B)} = 1.5 \text{ V}.$
- (3)  $V_{CC(B)} = 1.8 \text{ V}.$
- (4)  $V_{CC(B)} = 2.5 \text{ V}.$
- (5)  $V_{CC(B)} = 3.3 \text{ V}.$

Fig 12. Typical propagation delay versus load capacitance;  $T_{amb} = 25$  °C

# 13. Package outline

TSSOP48: plastic thin shrink small outline package; 48 leads; body width 6.1 mm

SOT362-1



#### Notes

- 1. Plastic or metal protrusions of 0.15 mm maximum per side are not included.
- 2. Plastic interlead protrusions of 0.25 mm maximum per side are not included.

OUTLINE		REFER	ENCES	EUROPEAN	ISSUE DATE	
VERSION	IEC	JEDEC	JEITA	PROJECTION	ISSUE DATE	
SOT362-1		MO-153			<del>99-12-27</del> 03-02-19	

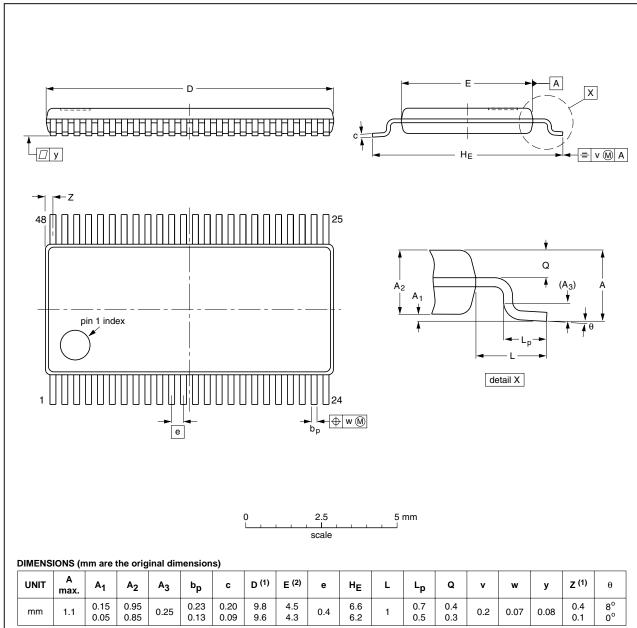
Fig 13. Package outline SOT362-1 (TSSOP48)

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# TSSOP48: plastic thin shrink small outline package; 48 leads; body width 4.4 mm; lead pitch 0.4 mm

SOT480-1



#### Notes

- 1. Plastic or metal protrusions of 0.15 mm maximum per side are not included.
- 2. Plastic interlead protrusions of 0.25 mm maximum per side are not included.

OUTLINE		REFER	EUROPEAN	ISSUE DATE		
VERSION	IEC	JEDEC	JEITA		PROJECTION	ISSUE DATE
SOT480-1		MO-153				<del>99-12-27</del> 03-02-18

Fig 14. Package outline SOT480-1 (TSSOP48)

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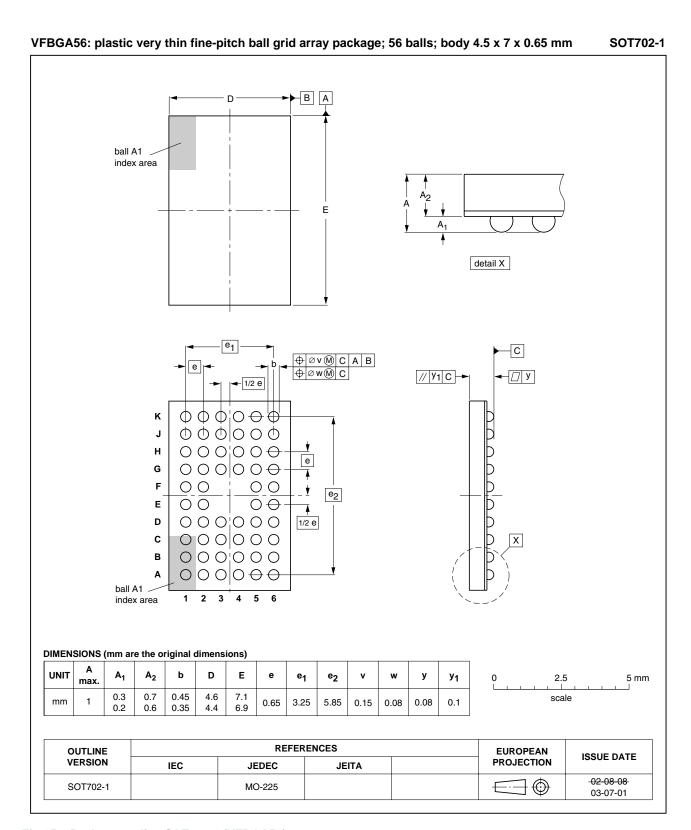


Fig 15. Package outline SOT702-1 (VFBGA56)

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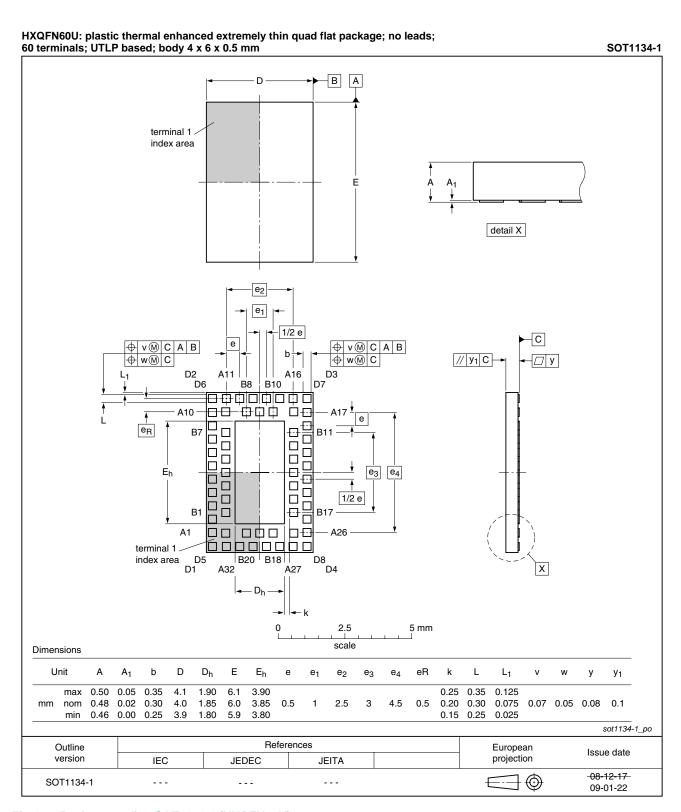


Fig 16. Package outline SOT1134-1 (HXQFN60U)

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### 14. Abbreviations

#### Table 16. Abbreviations

Acronym	Description
CDM	Charged Device Model
DUT	Device Under Test
ESD	ElectroStatic Discharge
НВМ	Human Body Model
MM	Machine Model

# 15. Revision history

#### Table 17. Revision history

Document ID	Release date	Data sheet status	Change notice	Supersedes
74AVCH16T245_2	20100329	Product data sheet	-	74AVCH16T245_1
Modifications:	<ul> <li>74AVCH16T</li> <li>package.</li> </ul>	245BQ changed from HUQFN	N60U (SOT1025-1) to	HXQFN60U (SOT1134-1)
74AVCH16T245_1	20091014	Product data sheet	-	-

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### 16. Legal information

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Document status[1][2]	Product status[3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
Product [short] data sheet	Production	This document contains the product specification.

- [1] Please consult the most recently issued document before initiating or completing a design.
- [2] The term 'short data sheet' is explained in section "Definitions"
- [3] The product status of device(s) described in this document may have changed since this document was published and may differ in case of multiple devices. The latest product status information is available on the Internet at URL <a href="http://www.nxp.com">http://www.nxp.com</a>.

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### 18. Contents

Features and benefits		. 2 . 2 . 4
<ul><li>Functional diagram</li></ul>		. <b>2</b> . <b>4</b>
<b>5 Pinning information</b> 5.1 Pinning		. <b>4</b> . 4
5.1 Pinning		. 4
3		
5.2 Pin description		. 6
6 Functional description		. 6
7 Limiting values		. 7
8 Recommended operating conditions		. 7
9 Static characteristics		. 8
10 Dynamic characteristics		12
11 Waveforms		
12 Typical propagation delay characteristi	ics	18
13 Package outline		22
14 Abbreviations		26
15 Revision history		26
16 Legal information		27
16.1 Data sheet status		
16.2 Definitions		27
16.3 Disclaimers		27
16.4 Trademarks		27
17 Contact information		28
18 Contents		29

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